

Notice of References Cited		Application/Control No. 09/940,544	Applicant(s)/Patent Under Reexamination LEE, JOUN HO	
		Examiner Steven H. Rao	Art Unit 2814	Page 1 of 1

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M	US-			

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NON-PATENT DOCUMENTS

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 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.